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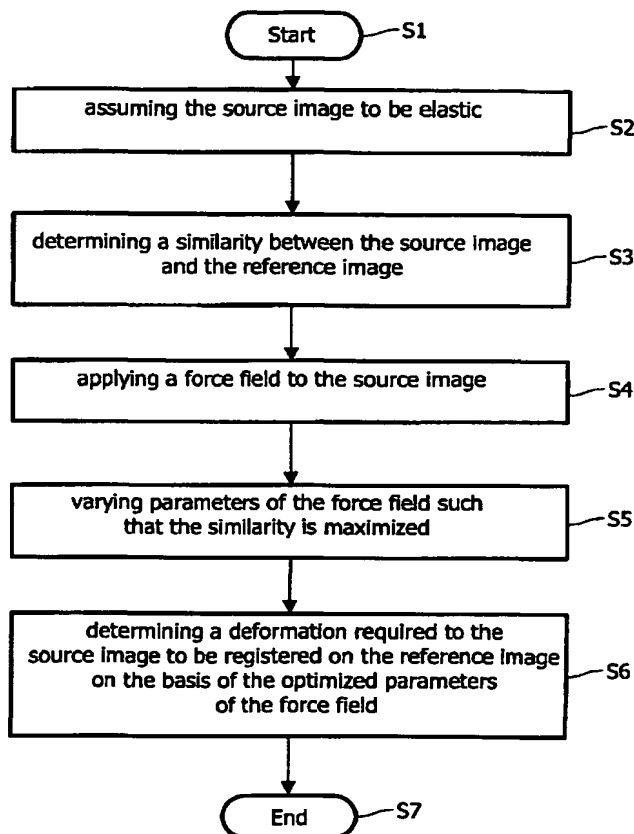
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(54) Title: ADAPTIVE POINT-BASED ELASTIC IMAGE REGISTRATION



(57) Abstract: The present invention aims at improving the point-based elastic registration paradigm. According to the present invention, a force field, for example, with Gaussian-shaped forces, is applied at several points to the image to be deformed. In this case, no landmark correspondences are required and the optimal positions of the force application point are found automatically, which minimizes the difference between the source and target image. Advantageously, this may allow to control a local influence of individual control points.

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